

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	7	((("5635410") or ("5804981") or ("5943552") or ("6136669") or ("6140131") or ("6423615") or ("6524928"))).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/16 14:03
S2	2304	wafer and impurity and transition metal	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 13:02
S3	860	S2 and @pd<"20030117"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 12:56
S4	32	S3 and quantitative analysis	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 12:57
S5	1	("5677253").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/14 13:04
S6	1	("6319845").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/14 13:04
S7	1	("5298860").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/14 13:06
S8	1	schottky metal detection	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/14 13:13
S9	685	schottky metal	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/14 13:13
S10	187	schottky metal and nickel	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/14 13:13
S11	1	("5943552").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/14 13:15

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S12	4	"5945332"	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/14 13:14
S13	17	"5943552"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 13:42
S14	539	436/73.ccls.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 13:59
S15	0	semiconductor and metal adj impurit and surface technique	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 13:59
S16	389	semiconductor and metal and surface technique	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:15
S17	0	vapor phase dposition	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:17
S18	6054	vapor phase deposition	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 16:51

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S19	1410	S18 and nickel	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:17
S20	1205	S19 and (semiconductor or wafer or substrate)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:18
S21	1242893	analysis or quantitative determination	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:19
S22	356	S20 and (analysis or quantitative determination)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:19
S23	6	S22 and hotplate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 14:20
S24	0	out diffusion of silicon	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 16:51
S25	0	("schottky").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/08/14 18:07

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S26	20590	schottky	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/14 18:08
S27	130	S26 and hot plate	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 18:12
S28	58	S27 and impurity	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/14 18:08
S29	5	"6440494"	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/16 08:39
S30	5	shabani.in.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/17 10:14
S31	2	("5849597" "6204188").PN.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/16 11:07
S32	444	436/73.ccls.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/16 11:07
S33	2108	wafer and cool and ethylene glycol	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/16 14:05
S34	61	S33 and cooling plate	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/16 14:06
S35	45	S34 and @pd<"20040117"	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/08/17 07:28
S36	3	((("5705089") or ("6194326") or ("6544338"))).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/17 07:28
S37	1	("20020101576").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2007/08/17 10:14